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Docket No.: T2171.0180/P180

(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Takahisa Yamaha

Allowed: June 25, 2004

Application No.: 09/518,709

Confirmation No.: 5749

Filed: March 3, 2000

Art Unit: 2815

For: MANUFACTURE METHOD FOR

SEMICONDUCTOR WITH SMALL VARIATION IN MOS THRESHOLD

VOLTAGE

Examiner: E. Ortiz

REQUEST FOR SUPPLEMENTAL NOTICE OF ALLOWANCE

Attn: MS Issue Fee Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Applicants received a Notice of Allowance dated June 25, 2004.

On March 12, 2001, Applicant filed a Information Disclosure Statement. During final review of the allowed application, Applicant note that the Information Disclosure Statement of March 12, 2001 was not acknowledged.

Applicant respectfully requests that the Information Disclosure Statement dated March 12, 2001 be acknowledged and considered for the above-referenced patent application, before payment of the issue fee. A copy of said Information Disclosure Statement, Applicant's Art Citation, References submitted on 03/12/2001 (plus stamped postcard indicating receipt by the U.S. Patent Office) are enclosed for your convenience.

Application No.: 09/518,709 Docket No.: T2171.0180/P180

Please charge any credits or deficiencies to our Deposit Account No. 50-2215.

Dated: August 3, 2004

Respectfully submitted,

Steven I. Weisburd

Registration No.: 27,409

DICKSTEIN SHAPIRO MORIN &

OSHINSKY LLP

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New York, New York 10036-2714

(212) 835-1400

Attorney for Applicant



	Serial No. 09/518, 709 Filling Date 3 Title MANUFACTURE METH First Inventor YAMAHA, T.	7 3-00 OFGS File No. P/2171-180 DD FDK SEMICONDUCTOR Date 3-12-01				
	The PTO has received:	Last Due Date:				
	☐ Patent Application of	☐ TM Application ☐ ITV Basis				
ſ	Pages (including claims & abstract)	Statement of Use				
	☐ Declaration or ☐ Designation Sheet	□ Extension of Time □ MAR 1 6 2001 □				
	☐ Drawings Sheet(s)/Figs to	□ Notice of Appeal				
	☐ Priority Document	□ Brief				
	☐ Small Entity Declaration	□ Petition				
•	☐ Assignment & Conveyance Cover Sheet	☐ Status Request PTO STAMP				
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Our Ref.: P/2171-180

Takahisa YAMAHA

Date: March 12, 2001

AUG 1 0 2004

Serial No.: 09/518,709

Group Art Unit: 2812

Filed: March 3, 2000

Examiner: --

For: MANUFACTURE METHOD FOR SEMICONDUCTOR WITH SMALL VARIATION IN MOS THRESHOLD

VOLTAGE

Assistant Commissioner of Patents
Washington, D.C., 20221

Washington, D.C. 20231

SUBMISSION

Sir:

Submitted herewith is a copy of art together with an art listing form listing the same for the convenience of the Examiner.

The Japanese Publication(s) listed on the attached art listing form was/were cited in a Japanese Office Action issued in a related application. A copy of the Office Action is attached. English-language Abstracts have been provided for the references.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Assistant Commissioner of Patents, Washington, D.C. 20231, on March 12, 2001.

Steven I. Weisburd
Name of applicant, assignee or
Registered Representative

Signature

March 12, 2001 Date of Signature Respectfully submitted,

Steven I. Weisburd

Registration No.: 27,409

OSTROLENK, FABER, GERB & SOFFEN, LLP

1180 Avenue of the Americas New York, New York 10036-8403

Telephone: (212) 382-0700

SIW:sks/Enclosures

APPLICANT'S ART CITATION								Application 09/518,709			OFGS File No. P/2171-180			
								Applicant YAMAHA, T.						
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Japanese Office Action issued July 4, 2000.														
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